

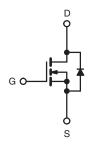
SPP02N80C3-VB Datasheet **Power MOSFET**

PRODUCT SUMMARY					
V _{DS} (V)	850				
R _{DS(on)} (Ω)	V _{GS} = 10 V 2.7				
Q _g (Max.) (nC)	78				
Q _{gs} (nC)	9.6				
Q _{gd} (nC)	45				
Configuration	Single				

FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C	= 25 °C, unl	less otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	850	Ň	
Gate-Source Voltage			V _{GS}	± 20	- V	
Continuous Drain Current	V + 10 V	T _C = 25 °C		4.1		
	V _{GS} at 10 V	T _C = 100 °C	ID	2.6	А	
Pulsed Drain Current ^a			I _{DM}	16		
Linear Derating Factor				1.0	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	260	mJ	
Avalanche Current ^a			I _{AR}	4.1	А	
Repetitive Avalanche Energy ^a			E _{AR}	13	mJ	
Maximum Power Dissipation	ation T _C = 25 °C			125	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for	10 s		300 ^d		
Mounting Torque	6.20 or 1	C 00 or M0 oprovi		10	lbf ⋅ in	
Mounting Torque	6-32 or M3 screw			1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 29 mH, $R_g = 25 \Omega$, $I_{AS} = 4.1 \text{ A}$ (see fig. 12). c. $I_{SD} \le 4.1 \text{ A}$, dl/dt $\le 100 \text{ A/}\mu\text{s}$, $V_{DD} \le 600 \text{ V}$, $T_J \le 150 \text{ °C}$. d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	-	62		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	-	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	1.0		

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							•
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D = 250 μΑ	850	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference	e to 25 °C, I _D = 1 mA	-	0.90	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μΑ	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 20 V	-	-	± 100	nA
		V _{DS} =	V _{DS} = 800 V, V _{GS} = 0 V		-	100	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 640 V	∕, V _{GS} = 0 V, T _J = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 2.5 A ^b	-	2.7	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	= 100 V, I _D = 2.5 A	2.5	-	-	S
Dynamic						•	•
Input Capacitance	C _{iss}		$V_{GS} = 0 V,$	-	1300	-	pF
Output Capacitance	C _{oss}		$V_{DS} = 25 V,$	-	310	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.	.0 MHz, see fig. 5	-	190	-	
Total Gate Charge	Qg		$V_{GS} = 10 \text{ V}$ $I_D = 4.1 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b		-	78	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V			-	9.6	
Gate-Drain Charge	Q _{gd}			-	-	45	1
Turn-On Delay Time	t _{d(on)}				12	-	- ns
Rise Time	t _r	$V_{DD}=400~V,~I_{D}=4.1~A, \label{eq:VDD}$ R_g = 12 $\Omega,~R_{D}$ = 95 $\Omega,~see~fig.~10^{b}$		-	33	-	
Turn-Off Delay Time	t _{d(off)}			-	82	-	
Fall Time	t _f			-	30	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L _S			-	7.5	-	nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	4.1	Α
Pulsed Diode Forward Current ^a	I _{SM}			-	-	16	
Body Diode Voltage	V_{SD}	$T_J = 25 \ ^{\circ}C, \ I_S = 4.1 \ A, \ V_{GS} = 0 \ V^b$		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 \text{ °C}, I_F = 4.1 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}^{b}$		-	480	720	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	1.8	2.7	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				L _D)	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

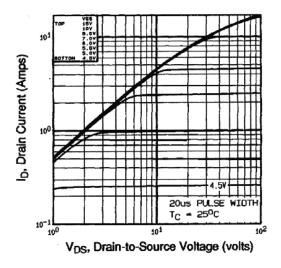


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

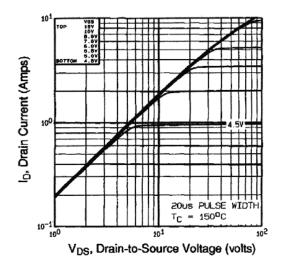


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

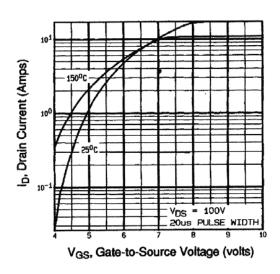


Fig. 3 - Typical Transfer Characteristics

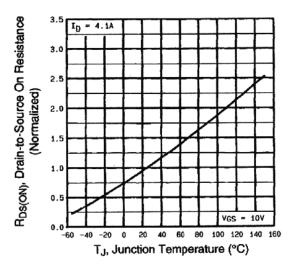


Fig. 4 - Normalized On-Resistance vs. Temperature



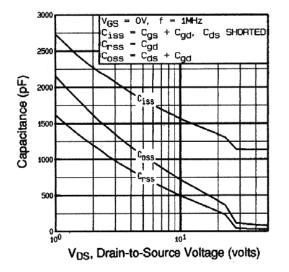


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

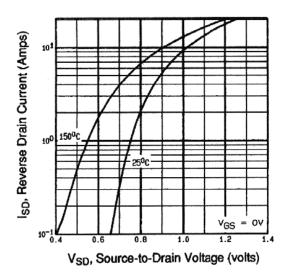


Fig. 7 - Typical Source-Drain Diode Forward Voltage

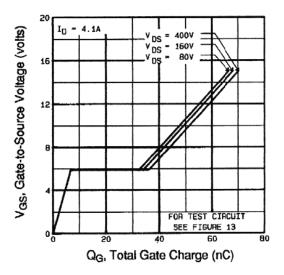
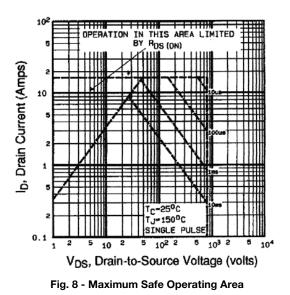


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





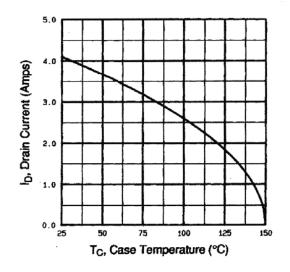


Fig. 9 - Maximum Drain Current vs. Case Temperature

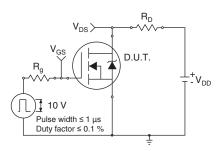


Fig. 10a - Switching Time Test Circuit

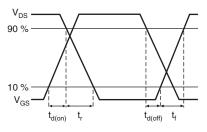
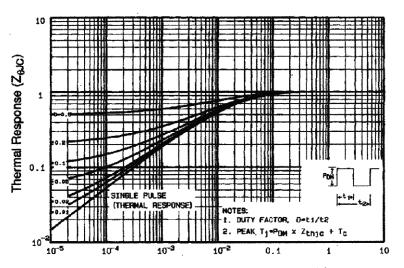
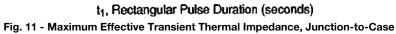


Fig. 10b - Switching Time Waveforms





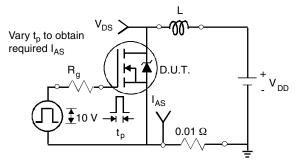


Fig. 12a - Unclamped Inductive Test Circuit

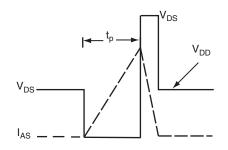


Fig. 12b - Unclamped Inductive Waveforms



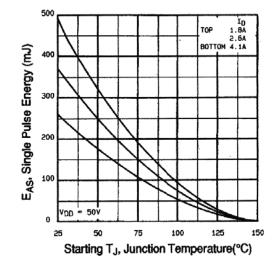


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

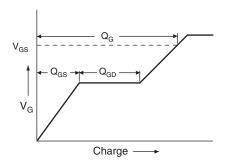


Fig. 13a - Maximum Avalanche Energy vs. Drain Current

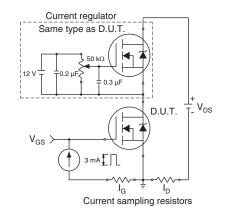
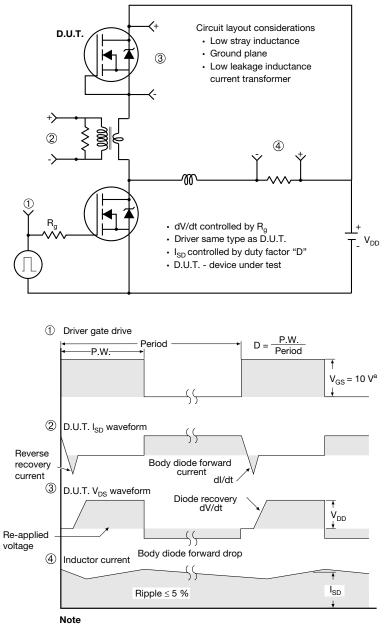


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

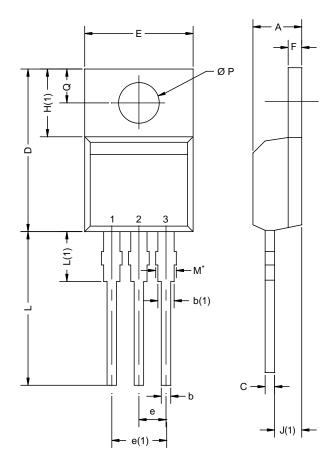


a. $V_{GS} = 5 \text{ V}$ for logic level devices

Fig. 14 - For N-Channel



TO-220AB



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
E	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
Ø P	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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